

FRONT-END

MOS-FET

IGBT

DIODE

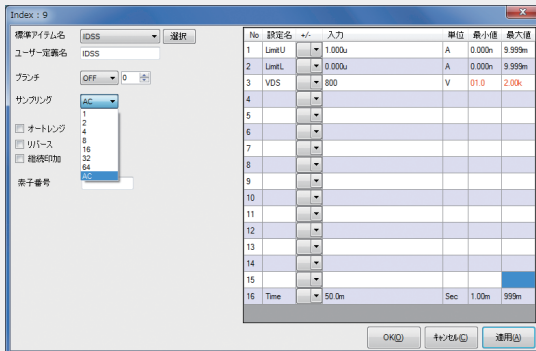
SEMICONDUCTOR TEST SYSTEM / INDUCTIVE LOAD TESTER 半導体テストシステム / L 負荷テスター

CHT2020ZC/LVNJ20ZFCA 2000V
200A

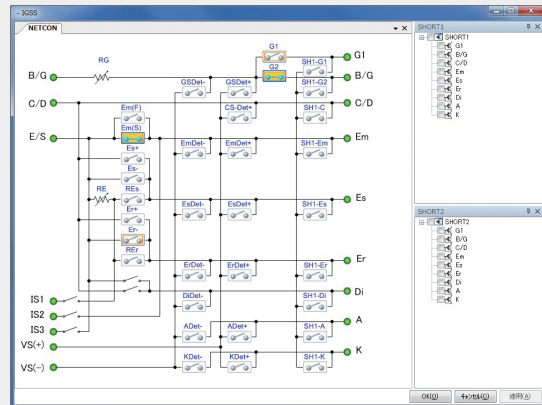
- This system can carry out DC and inductive load test at measurement unit of overhead mechanism in consideration of wafer measurement with prober by continuance.
- It has high-speed power supply break function by the protection circuit in head box at unusual waveform detection with inductive load test.
- 本器は、プローバーでのウェハ測定を考慮した、オーバーヘッド機構の測定部により、DC 測定と L 負荷測定を連続でできるテストシステムです。
- L 負荷測定での異常波形検出時は、ヘッドボックス内の保護回路により、高速で電源を遮断する機能が装備されています。



Software Display



NETCON Setting



MODEL

CHT2020ZC/LVNJ20ZFCA

SOFTWARE

TEST PLAN/SORT PLAN

1000/1000

BIN OUT

24

DC TEST

MEASURABLE DEVICES

N/P MOS-FET, N/P-IGBT, N/P-DIODE

VOLTAGE/CURRENT

2000V/200A

TEST ITEMS

MOS-FET

IDS, IDG, HIDS, HIDG, IGsx, IGss, ISGS, BVds, BVdG, BVsG, VFdG, VFgs, VFSDs, VFSDs+, VP,

VTH, VTH2, VdsON, RdsON, IdON, DHIDSS, GMP

IGBT

ICE, IGES, BVCE, ILGES+, ILGES-, VTHGB1, VTHGB2, VBLMK, VBLMK+, VBLMK-, HVBLMK, HVBLMK+, HVBLMK-, VEmE, VEmE2, VEmER1, VEs1ECS, VEmER2, VGEEm, IEmE1, IEs1ECES, IEmE2, BVCEmX2+, BVCEmX2-, BVGESP, VGEI1, VGEI2, HICEX+, HICEX-, HICG, HICG+, HICG-, ICEX+, ICEX-, LIGE, HIGE, IGE, ILCEEes, VCEsON, VCErON, VCEON, ICEON, IAE, HIAE, IEmA, BVEG, IEsEm, IEmEs, HIEsEm, HIEmEs

DIODE

VF, LVF, VFCD, VRD, IRD, HIRD, LIRD, VFD, LVFD, ThDivF, ThDivZ, ThDivZ, LThDivZ

INDUCTIVE LOAD TEST

MEASURABLE DEVICES

N/P MOS-FET

SETTING RANGE

VDD

1V~200V

ID/IL

0.2A~200A

VGF/VGR

0.1V~39.9V

VD LIMIT

10V~2000V

ON TIME

0.0001ms~9.9999ms

DETECT DELAY

0.1μs~9.9μs

Rg SELECT

6 circuit select is possible

DIMENSIONS & WEIGHT

MAIN UNIT

550(W)×860(D)×1700(H)---270kg

MEASUREMENT UNIT

1510(W)×1170(D)×1840(H)---260kg